

Notice of References Cited	Application/Control No. 10/712,415	Applicant(s)/Patent Under Reexamination MARIO ET AL.	
	Examiner Allen C. Ho	Art Unit 2882	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,879,657 B2	04-2005	Hoffman, David Michael	378/7
	B	US-5,956,382	09-1999	Wiener-Avnear et al.	378/98.8
	C	US-5,936,247	08-1999	Lange et al.	250/363.03
	D	US-5,308,986	05-1994	Walker, James K.	250/370.11
	E	US-5,253,283	10-1993	Annis et al.	378/98.7
	F	US-4,893,015	01-1990	Kubierschky et al.	250/369
	G	US-4,884,289	11-1989	Glockmann et al.	378/57
	H	US-4,879,752	11-1989	Aune et al.	382/141
	I	US-4,651,002	03-1987	Anno, Hidero	250/336.1
	J	US-4,626,688	12-1986	Barnes, Gary T.	250/361R
	K	US-4,029,963	06-1977	Alvarez et al.	378/5
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nicholas Tsoulfanidis. MEASUREMENTS AND DETECTION OF RADIATION, second edition, p. 218 - 221. Taylor & Francis, Washington, DC., 1995.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.